

## Supporting Information

### Improved thermoelectric performance of copper-deficient compounds $\text{Cu}_{2.5+\delta}\text{In}_{4.5}\text{Te}_8$ ( $\delta=0\text{-}0.15$ ) with an excess of Cu caused by formation of impurity bands and reduction in lattice thermal conductivity

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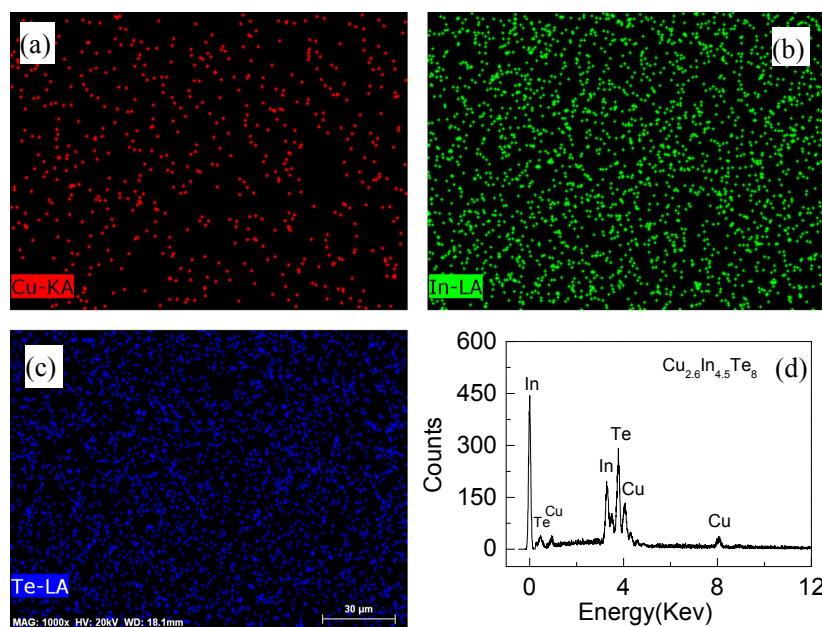


Fig. S1 EPMA mappings of three elements on polished  $\text{Cu}_{2.6}\text{In}_{4.5}\text{Te}_8$  surface  
(a) Cu, (b) In, (c) Te, (d) an EDAX pattern.

Table S1 Average chemical compositions (relative molars) identified in  $\text{Cu}_{2.5}\text{In}_{4.5}\text{Te}_8$  and  $\text{Cu}_{2.6}\text{In}_{4.5}\text{Te}_8$  (taken from different mappings)

Compounds	Cu	In	Te
$\text{Cu}_{2.5}\text{In}_{4.5}\text{Te}_8$	2.53	4.51	8.0
$\text{Cu}_{2.6}\text{In}_{4.5}\text{Te}_8$	2.62	4.53	8.0

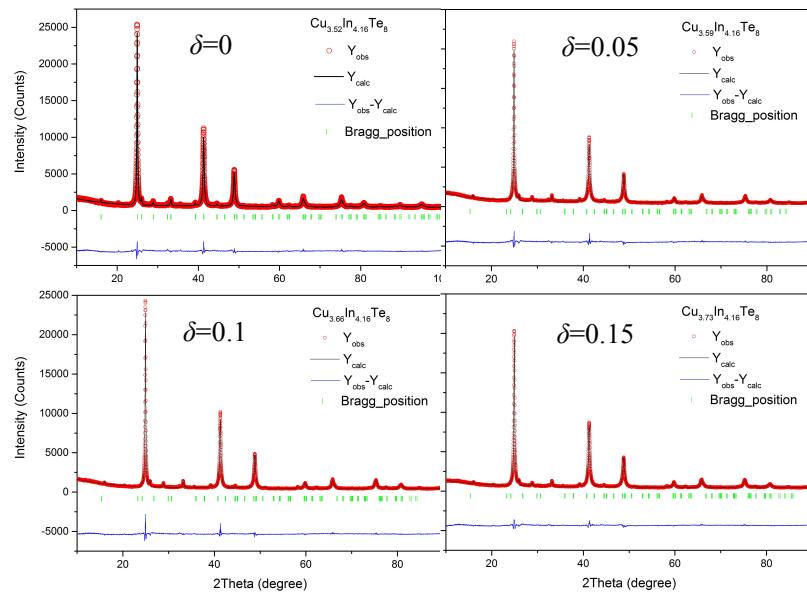


Fig. S2 Rietveld refinements using X-ray diffraction data of four compounds  $\text{Cu}_{2.5+\delta}\text{In}_{4.5}\text{Te}_8$  ( $\delta=0, 0.05, 0.1, 0.15$ ).

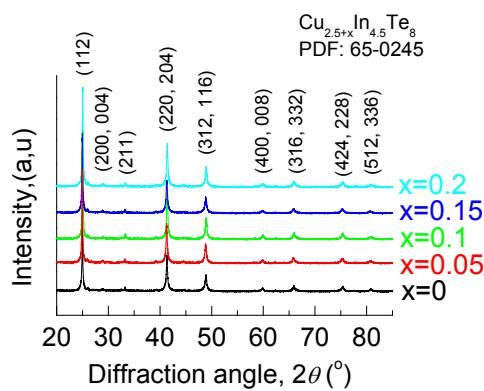


Fig. S3 XRD patterns of the powders of  $\text{Cu}_{2.5+\delta}\text{In}_{4.5}\text{Te}_8$  ( $\delta=0, 0.05, 0.1, 0.15, 0.2$ ).

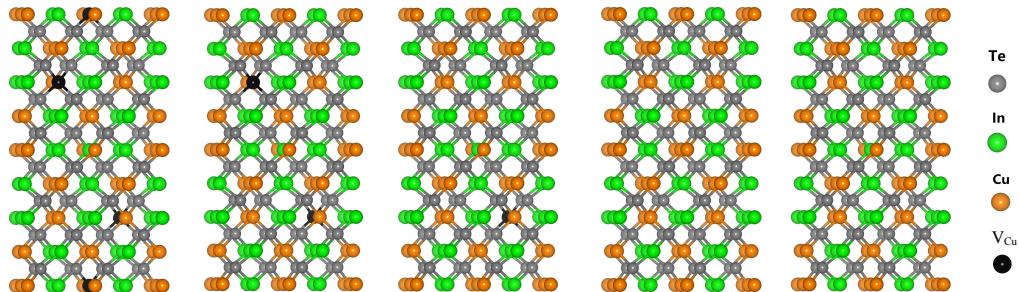


Fig. S4 Crystal structures of Cu<sub>28+y</sub>In<sub>33</sub>Te<sub>64</sub> ( $y=0-4$ ) assuming that added Cu atoms reside in the Cu vacancy.

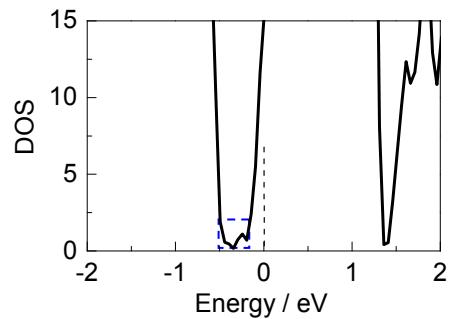


Fig. S5 Close-up view of the impurity band (IB) in the density of states (DOS) of Cu<sub>28+y</sub>In<sub>33</sub>Te<sub>64</sub> ( $y=0-4$ ) system.

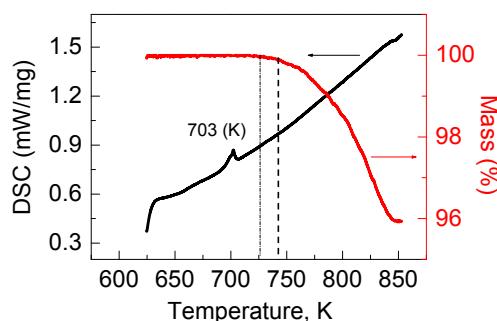


Fig. S6 Differential scanning calorimetry (DSC) and weight loss (TG) signals as a function of temperature for Cu<sub>2.5</sub>In<sub>4.5</sub>Te<sub>8</sub>.